

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10576899	PAILA ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
MARCOS BATISTA	2617	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	329	5/13/2008	mb
370	314	5/13/2008	mb
455	343.1-343.4	12/2/2008	mb
713	300, 323, 320, 324	12/2/2008	mb

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Consulted with TA - Yogesh Aggarwal	5/13/2008	mb
Consulted with Lun-YI Lao	5/13/2008	mb
East Search	5/13/2008	mb
Inventor's Name Search	5/13/2008	mb
East Search	12/2/2008	mb
Consulted with Rafael Perez Gutierrez	3/17/2009	mb

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>